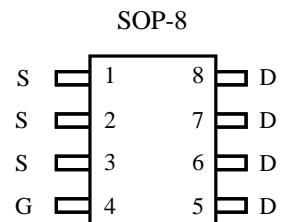


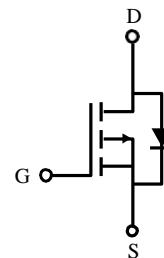
## N-Channel High Density Trench MOSFET

### Features:

- Super high dense cell trench design for low RDS(on).
- Rugged and reliable.
- Surface Mount package.



<b>PRODUCT SUMMARY</b>		
V <sub>(BR)DSS</sub>	R <sub>D(S(on))</sub> (mΩ) Max	I <sub>D</sub>
60V	39 @ V <sub>GS</sub> =10V	8A
	46 @ V <sub>GS</sub> =4.5V	6A



### ABSOLUTE MAXIMUM RATINGS (TA = 25 °C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	60	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuousa T <sub>C</sub> = 25 °C	I <sub>D</sub>	10	A
	I <sub>DM</sub>	40	
Maximum Power Dissipation (Note 1)	P <sub>D</sub>	1.7	W
		1	
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	- 55 to 150	°C

### THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Ambient (Note 1)	R <sub>thJA</sub>	48	°C/W
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Note:

1. Surface Mounted on FR4 Board , t ≤ 10sec .

**ELECTRICAL CHARACTERISTICS (TA = 25 °C unless otherwise noted)**

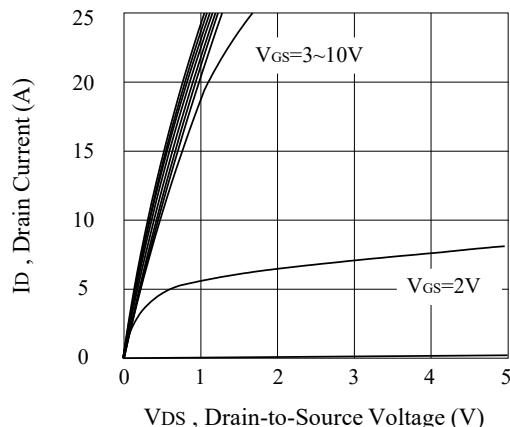
Parameter	Symbol	Condition	Min	Typ	Max	Unit
<b>OFF CHARACTERISTICS</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	60			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48V, V_{GS} = 0V$			1	$\mu A$
Gate-Body Leakage	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	$nA$
<b>ON CHARACTERISTICS (Note 3)</b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1	1.7	2.5	V
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 8A$		33	39	$m\Omega$
		$V_{GS} = 4.5V, I_D = 6A$		36	46	$m\Omega$
Forward Transconductance	$g_{fs}$	$V_{DS} = 5V, I_D = 5A$		10		S
<b>DYNAMIC CHARACTERISTICS (Note 4)</b>						
Input Capacitance	$C_{ISS}$	$V_{DS} = 30V, V_{GS} = 0V$ $f = 1.0MHz$		1112		pF
Output Capacitance	$C_{OSS}$			63		pF
Reverse Transfer Capacitance	$C_{RSS}$			42		pF
<b>SWITCHING CHARACTERISTICS (Note 4)</b>						
Turn-On Delay Time	$t_{d(ON)}$	$V_{DS} = 30V, I_D = 1A$ $V_{GS} = 10V$ $R_{GS} = 6\Omega, R_L = 15\Omega$		6.1		nS
Rise Time	$t_r$			23		nS
Turn-Off Delay Time	$t_{d(OFF)}$			43		nS
Fall Time	$t_f$			22		nS
Total Gate Charge	$Q_g$	$V_{DS} = 30V, I_D = 8A$ $V_{GS} = 10V$		27		nC
Gate-Source Charge	$Q_{gs}$			3.8		nC
Gate-Drain Charge	$Q_{gd}$			4.7		nC
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
Drain-Source Diode Forward Current (Note 1)	$I_S$			6		A
Diode Forward Voltage (Note 3)	$V_{SD}$	$V_{GS} = 0V, I_S = 1.0A$		0.77	1.1	V

Note:

3. Pulse Test Pulse width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$ .

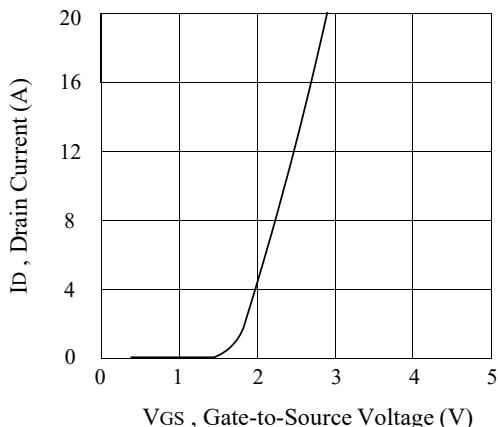
4. Guaranteed by design, not subject to production testing.

## N-Channel High Density Trench MOSFET



V<sub>DS</sub> , Drain-to-Source Voltage (V)

Figure 1. Output Characteristics



V<sub>GS</sub> , Gate-to-Source Voltage (V)

Figure 2. Transfer Characteristics

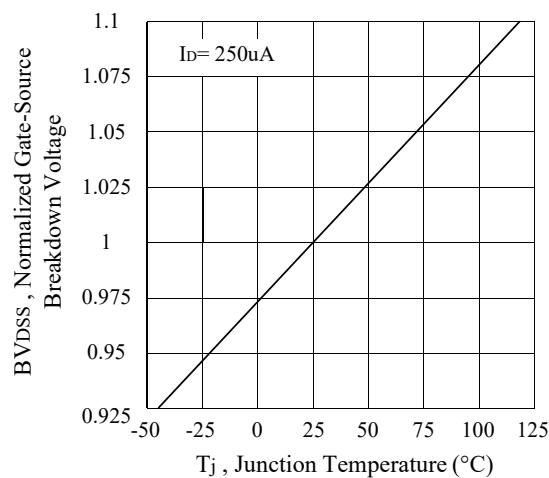


Figure 3. Breakdown Voltage Variation with Temperature

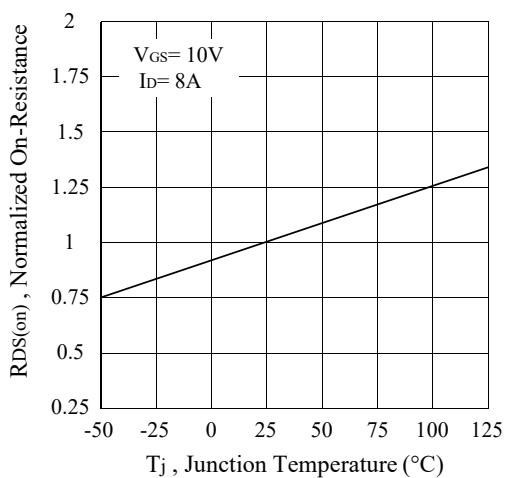


Figure 4. On-Resistance Variation with Temperature

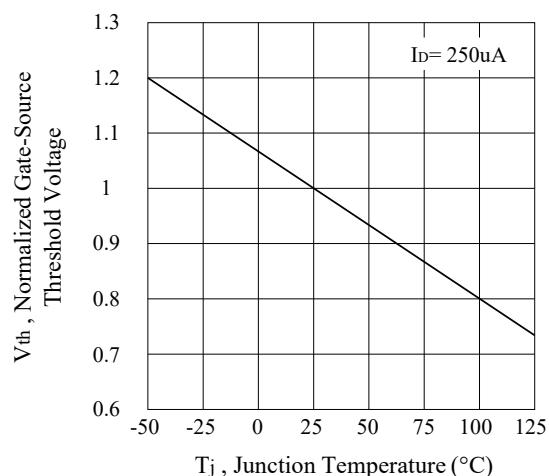


Figure 5. Gate Threshold Variation with Temperature

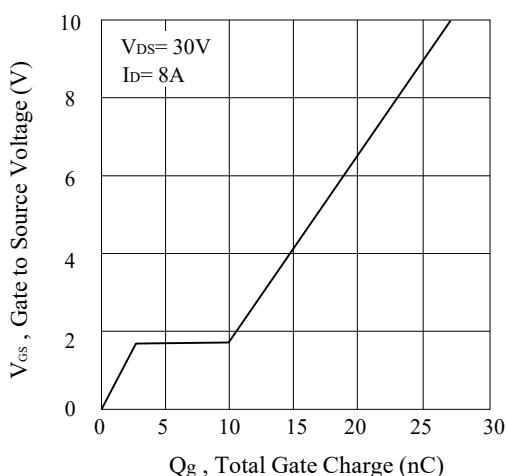


Figure 6. Gate Charge

## N-Channel High Density Trench MOSFET

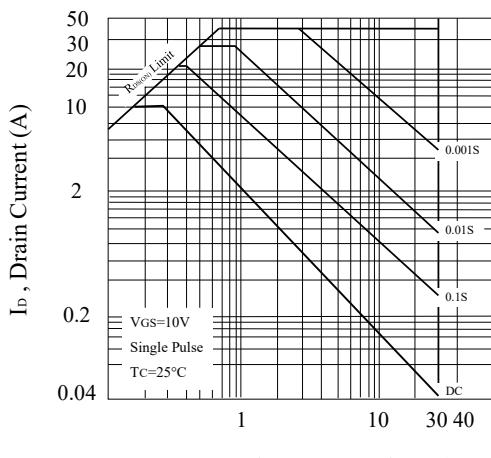


Figure 7. Maximum Safe Operating Area

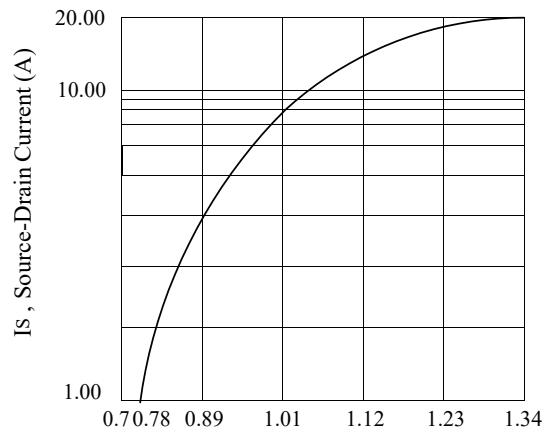


Figure 8. Body Diode Forward Voltage Variation with Source Current

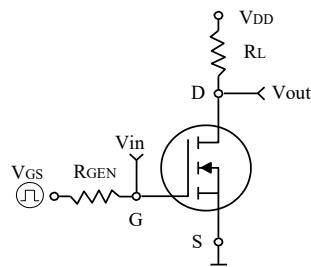


Figure 9. Switching Test Circuit and Switching Waveforms

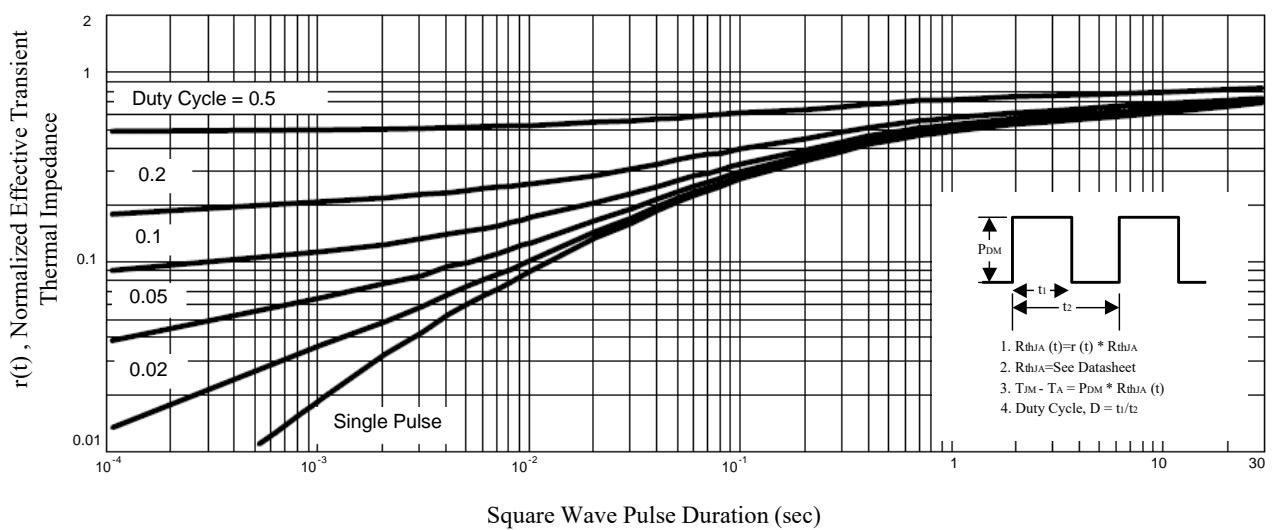
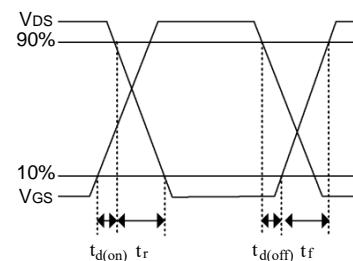


Figure 10. Normalized Thermal Transient Impedance Curve